

# SN54ALS03B, SN74ALS03B QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS WITH OPEN-COLLECTOR OUTPUTS

SDAS013B – MARCH 1984 – REVISED DECEMBER 1994

- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

## description

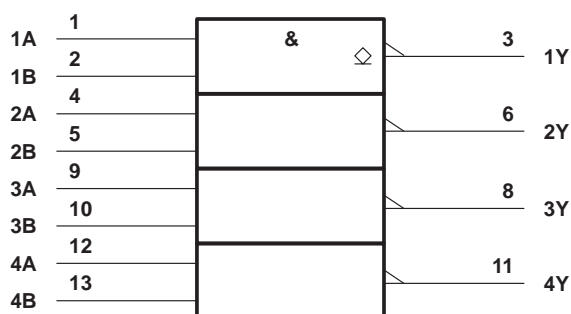
These devices contain four independent 2-input positive-NAND buffers. They perform the Boolean functions  $Y = \overline{A \cdot B}$  or  $Y = \overline{A + B}$  in positive logic. The open-collector outputs require pullup resistors to perform correctly. These outputs may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate high  $V_{OH}$  levels.

The SN54ALS03B is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN74ALS03B is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

FUNCTION TABLE  
(each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

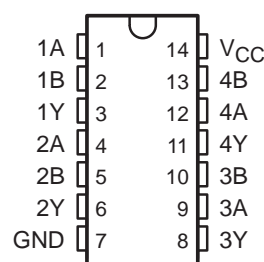
## logic symbol†



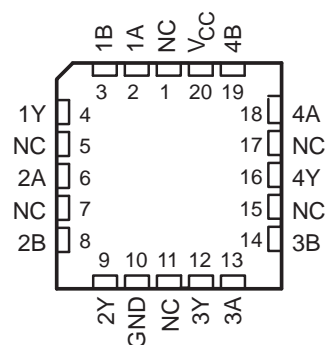
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

SN54ALS03B . . . J PACKAGE  
SN74ALS03B . . . D OR N PACKAGE  
(TOP VIEW)

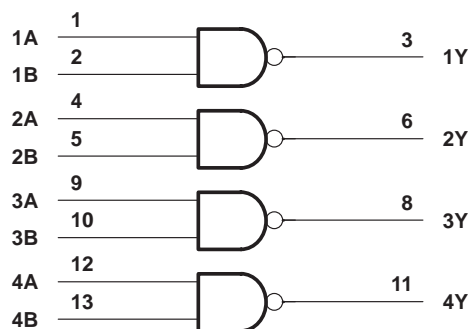


SN54ALS03B . . . FK PACKAGE  
(TOP VIEW)



NC – No internal connection

## logic diagram (positive logic)



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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, $V_{CC}$	7 V
Input voltage, $V_I$	7 V
Off-state output voltage	7 V
Operating free-air temperature range, $T_A$ : SN54ALS03B	–55°C to 125°C
SN74ALS03B	0°C to 70°C
Storage temperature range	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## recommended operating conditions

		SN54ALS03B			SN74ALS03B			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
$V_{CC}$	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.7			0.8	V
$V_{OH}$	High-level output voltage			5.5			5.5	V
$I_{OL}$	Low-level output current			4			8	mA
$T_A$	Operating free-air temperature	–55		125	0		70	°C

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	SN54ALS03B			SN74ALS03B			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
$V_{IK}$	$V_{CC} = 4.5$ V, $I_I = -18$ mA			–1.5			–1.5	V
$V_{OL}$	$V_{CC} = 4.5$ V, $I_{OL} = 4$ mA		0.25	0.4		0.25	0.4	V
						0.35	0.5	
$I_I$	$V_{CC} = 5.5$ V, $V_I = 7$ V			0.1			0.1	mA
$I_{IH}$	$V_{CC} = 5.5$ V, $V_I = 2.7$ V			20			20	μA
$I_{IL}$	$V_{CC} = 5.5$ V, $V_I = 0.4$ V			–0.1			–0.1	mA
$I_{OH}$	$V_{CC} = 4.5$ V, $V_{OH} = 5.5$ V			0.1			0.1	mA
$I_{CCH}$	$V_{CC} = 5.5$ V, $V_I = 0$		0.43	0.85		0.43	0.85	mA
$I_{CCL}$	$V_{CC} = 5.5$ V, $V_I = 4.5$ V		1.62	3		1.62	4	mA

‡ All typical values are at  $V_{CC} = 5$  V,  $T_A = 25^\circ\text{C}$ .

## switching characteristics (see Figure 1)

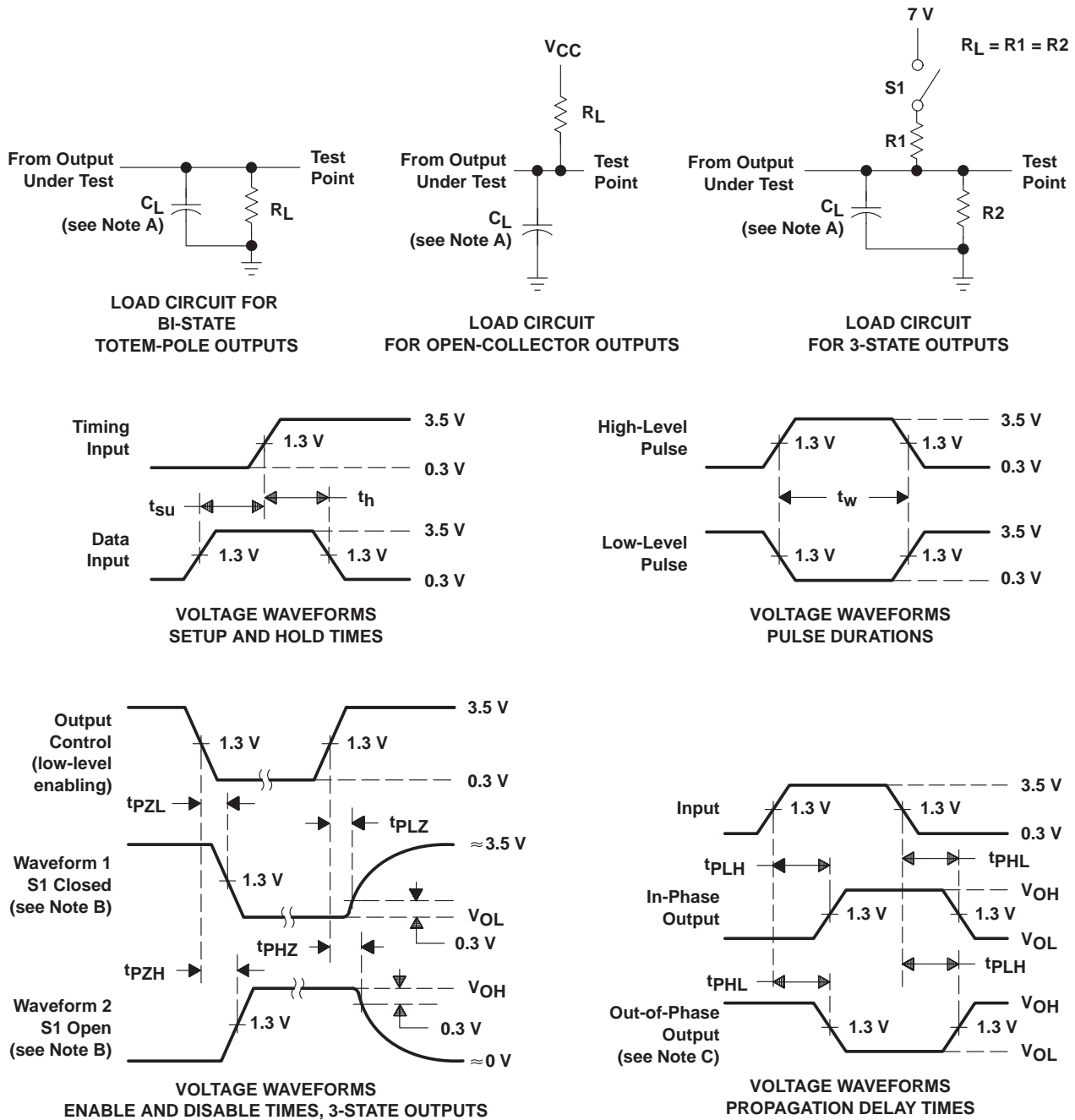
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 4.5$ V to 5.5 V, $C_L = 50$ pF, $R_L = 2$ kΩ, $T_A = \text{MIN to MAX}$ §				UNIT
			SN54ALS03B		SN74ALS03B		
			MIN	MAX	MIN	MAX	
$t_{PLH}$	A or B	Y	20	59	20	50	ns
$t_{PHL}$			3	23	3	13	

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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 WITH OPEN-COLLECTOR OUTPUTS**  
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**PARAMETER MEASUREMENT INFORMATION  
 SERIES 54ALS/74ALS AND 54AS/74AS DEVICES**



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 C. When measuring propagation delay items of 3-state outputs, switch S1 is open.  
 D. All input pulses have the following characteristics:  $PRR \leq 1$  MHz,  $t_r = t_f = 2$  ns, duty cycle = 50%.  
 E. The outputs are measured one at a time with one transition per measurement.

**Figure 1. Load Circuits and Voltage Waveforms**

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